



#22/Letter to
Draftman
8.12.03
C. Moore

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Inventors: James M. Holden; William A. McGahan; Richard A. Yarussi; Pablo I. Rovira; Roger R. Lowe-Webb
Assignee: Nanometrics Incorporated
Title: Apparatus And Method For The Measurement Of Diffracting Structures
Serial No.: 09/670,000 Filing Date: September 25, 2000
Examiner: Chih-Cheng Glen Kao Group Art Unit: 2882
Docket No.: NAN022 US Confirmation No. 3656

Santa Clara, California
January 10, 2003

COMMISSIONER FOR PATENTS
Washington, D. C. 20231

PROPOSED AMENDMENT TO DRAWINGS PURSUANT TO MPEP §608.02(r)

Dear Sir:

This Proposed Amendment to Drawings Pursuant to MPEP §608.02(r) is in response to the September 13, 2002, Office Action and accompanies the response to that office action. A Petition for Extension of Time under 37 CFR 1.136(a) is attached hereto, giving Applicants until January 13, 2003 to respond.

In the Drawings

Please amend Fig. 1 and Fig. 3 as shown in red on the attached sheets. Fig. 1 has been amended to include labels in #102, 122, 126, 130, 136, and 134, as described in the specification in the paragraphs starting at page 4, line 29 and ending on page 6, line 31. Fig. 3 is amended delete box 256, change the reference number of box 254 to 256 and to include a new box 254, all of which is described in the specification at the paragraph starting on page 7, line 21 and ending on line 30. Thus, no new matter is added.

Upon the Examiner's indication that the proposed drawings are acceptable, Formal Drawings incorporating the changes will be filed.

Should the Examiner have any questions concerning this response, the Examiner is invited to call the undersigned at (408) 982-8200, ext. 2.

Via Express Mail Label No.
EU 789 864 389 US

Respectfully submitted,

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